

# **MOSFET**

# **StrongIRFET™ 2 Power-Transistor**

#### **Features**

- Optimized for a wide range of applications
  N-Channel, normal level
  100% avalanche tested

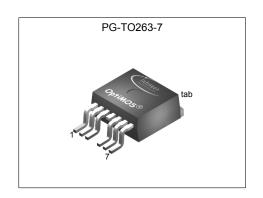
- Pb-free lead plating; RoHS compliant
  Halogen-free according to IEC61249-2-21

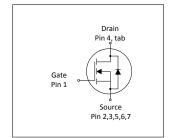
#### **Product validation**

Qualified according to JEDEC Standard

Table 1 **Key Performance Parameters** 

Table 1 Reg 1 direction and the control of the cont								
Parameter	Value	Unit						
$V_{ extsf{DS}}$	100	V						
R <sub>DS(on),max</sub>	1.6	mΩ						
I <sub>D</sub>	274	A						
Qoss	204	nC						
Q <sub>G</sub>	161	nC						











Type / Ordering Code	Package	Marking	Related Links
IPF016N10NF2S	PG-TO263-7	016N10NS	-

# StrongIRFET<sup>TM</sup> 2 Power-Transistor



# **Table of Contents**

escription	1
1aximum ratings	3
hermal characteristics	3
lectrical characteristics	4
lectrical characteristics diagrams	6
ackage Outlines	0
evision History	1
rademarks 1	1
nisclaimer	1

## StrongIRFET<sup>™</sup> 2 Power-Transistor **IPF016N10NF2S**



# 1 Maximum ratings at $T_A$ =25 °C, unless otherwise specified

Table 2 Maximum ratings

Danamatan	0		Value	s		
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Continuous drain current <sup>1)</sup>	I <sub>D</sub>	- - -	- - -	274 210 194 34	A	V <sub>GS</sub> =10 V, T <sub>C</sub> =25 °C V <sub>GS</sub> =10 V, T <sub>C</sub> =100 °C V <sub>GS</sub> =6 V, T <sub>C</sub> =100 °C V <sub>GS</sub> =10V, T <sub>A</sub> =25 °C, R <sub>thJA</sub> =40 °C/W <sup>2</sup> )
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	-	-	1096	Α	<i>T</i> <sub>A</sub> =25 °C
Avalanche energy, single pulse <sup>4)</sup>	E <sub>AS</sub>	-	-	1065	mJ	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 $\Omega$
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-
Power dissipation	P <sub>tot</sub>	-	-	300 3.8	W	T <sub>C</sub> =25 °C T <sub>A</sub> =25 °C, R <sub>thJA</sub> =40 °C/W <sup>2)</sup>
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55	-	175	°C	-

#### 2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Ullit	Note / Test Condition
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	0.5	°C/W	-
Thermal resistance, junction - ambient, 6 cm² cooling area²)		-	-	40	°C/W	-
Thermal resistance, junction - ambient, minimal footprint	R <sub>thJA</sub>	-	-	62	°C/W	-

<sup>&</sup>lt;sup>1)</sup> Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.  $^{2)}$  Device on 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain

connection. PCB is vertical in still air.

3) See Diagram 3 for more detailed information

4) See Diagram 13 for more detailed information

# StrongIRFET<sup>™</sup> 2 Power-Transistor IPF016N10NF2S



### **Electrical characteristics**

at T<sub>j</sub>=25 °C, unless otherwise specified

**Static characteristics** Table 4

Daniel de la constant	0		Value	s			
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	100	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	
Gate threshold voltage	V <sub>GS(th)</sub>	2.2	3.0	3.8	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =267 μA	
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1 10	1 100	μA	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	
Gate-source leakage current	I <sub>GSS</sub>	-	10	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	1.4 1.7	1.6 2.1	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =100 A V <sub>GS</sub> =6 V, I <sub>D</sub> =50 A	
Gate resistance	R <sub>G</sub>	-	1.4	-	Ω	-	
Transconductance <sup>1)</sup>	<b>g</b> fs	133	-	_	S	V <sub>DS</sub>  ≥2  I <sub>D</sub>   R <sub>DS(on)max</sub> , I <sub>D</sub> =100 A	

Table 5 **Dynamic characteristics** 

Devementar	Crossball	Values				Nata / Table Open distant
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance	C <sub>iss</sub>	-	11000	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz
Output capacitance	Coss	-	1700	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz
Reverse transfer capacitance	C <sub>rss</sub>	-	76	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz
Turn-on delay time	$t_{\sf d(on)}$	-	25	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Rise time	t <sub>r</sub>	-	65	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Turn-off delay time	$t_{\sf d(off)}$	-	60	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Fall time	t <sub>f</sub>	-	33	_	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$

Gate charge characteristics<sup>2)</sup> Table 6

Doromotor	Symbol		Values			Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Gate to source charge	Q <sub>gs</sub>	-	51	-	nC	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge at threshold	$Q_{g(th)}$	-	34	-	nC	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate to drain charge	$Q_{gd}$	-	33	-	nC	V <sub>DD</sub> =50 V, I <sub>D</sub> =100 A, V <sub>GS</sub> =0 to 10 V
Switching charge	Q <sub>sw</sub>	-	49	-	nC	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total <sup>1)</sup>	Qg	-	161	241	nC	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate plateau voltage	V <sub>plateau</sub>	-	4.5	-	V	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total, sync. FET	Q <sub>g(sync)</sub>	-	140	-	nC	V <sub>DS</sub> =0.1 V, V <sub>GS</sub> =0 to 10 V
Output charge	Qoss	-	204	-	nC	V <sub>DS</sub> =50 V, V <sub>GS</sub> =0 V

 $<sup>^{1)}</sup>$  Defined by design. Not subject to production test.  $^{2)}$  See "Gate charge waveforms" for parameter definition

# StrongIRFET<sup>TM</sup> 2 Power-Transistor IPF016N10NF2S

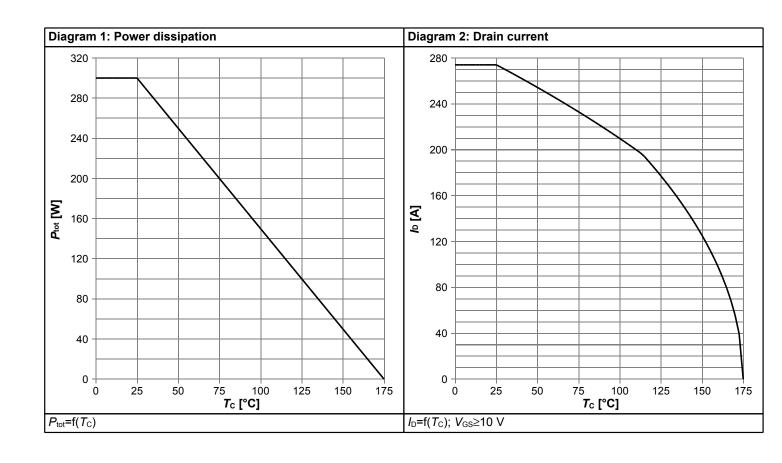


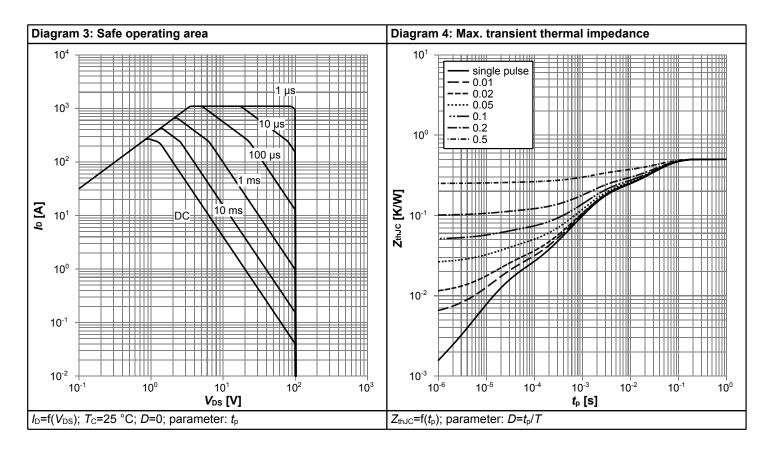
### Table 7 Reverse diode

Parameter	Cymphol		Values			Nata / Tank Oam distant
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Diode continuous forward current	Is	-	-	205	Α	<i>T</i> <sub>C</sub> =25 °C
Diode pulse current	I <sub>S,pulse</sub>	-	-	1096	Α	<i>T</i> <sub>C</sub> =25 °C
Diode forward voltage	V <sub>SD</sub>	-	0.86	1.2	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =100 A, T <sub>j</sub> =25 °C
Reverse recovery time	<i>t</i> <sub>rr</sub>	-	49	-	ns	V <sub>R</sub> =50 V, I <sub>F</sub> =100 A, d <i>i</i> <sub>F</sub> /d <i>t</i> =500 A/μs
Reverse recovery charge	Qrr	-	437	-	nC	$V_{R}$ =50 V, $I_{F}$ =100 A, $di_{F}/dt$ =500 A/ $\mu$ s

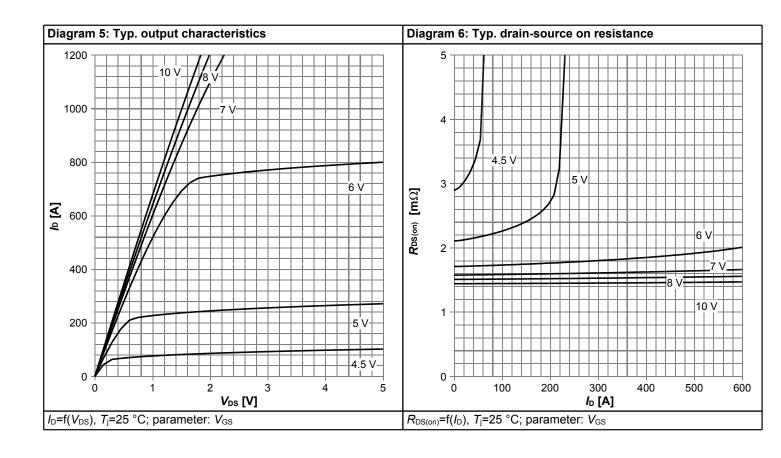


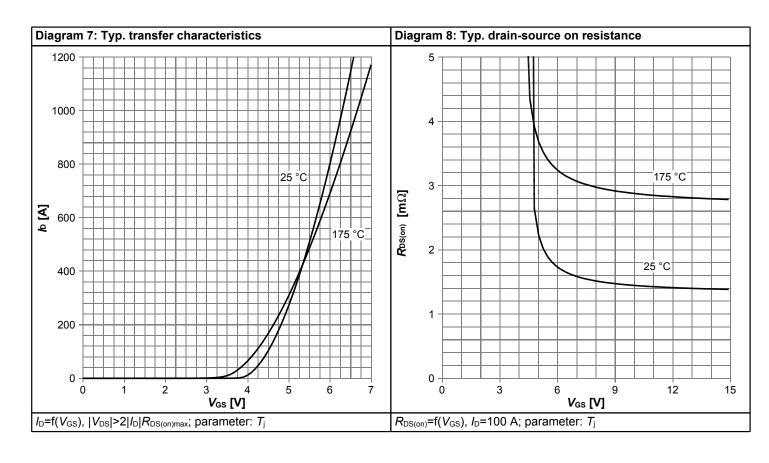
# 4 Electrical characteristics diagrams



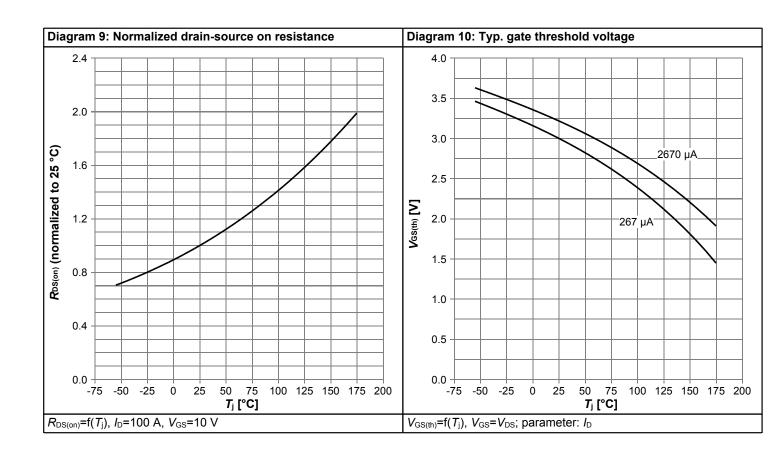


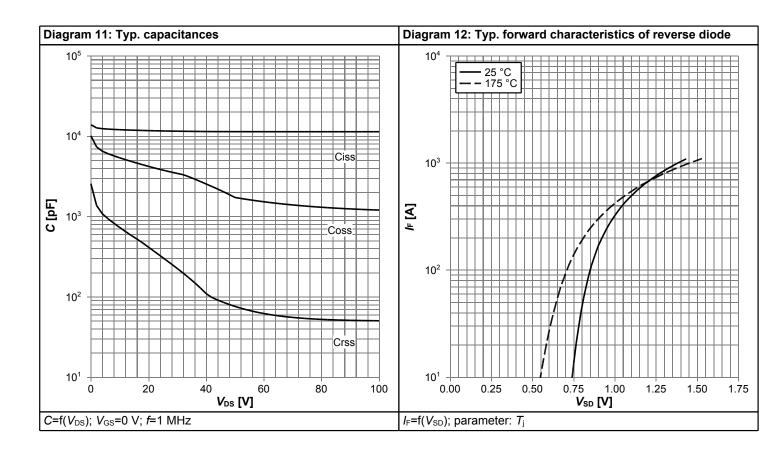




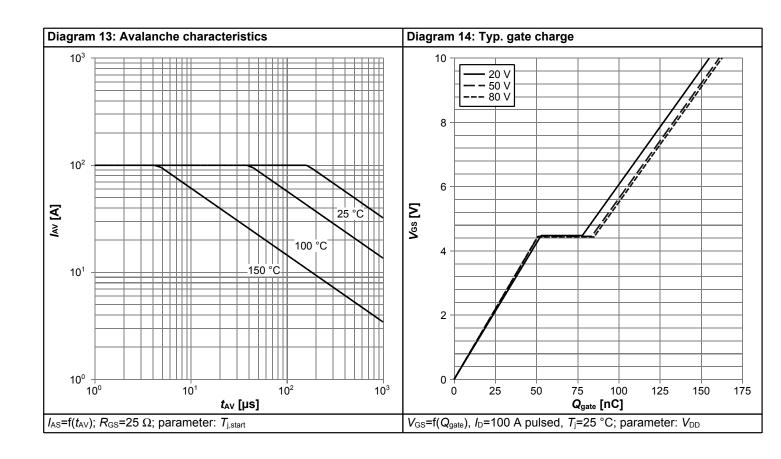


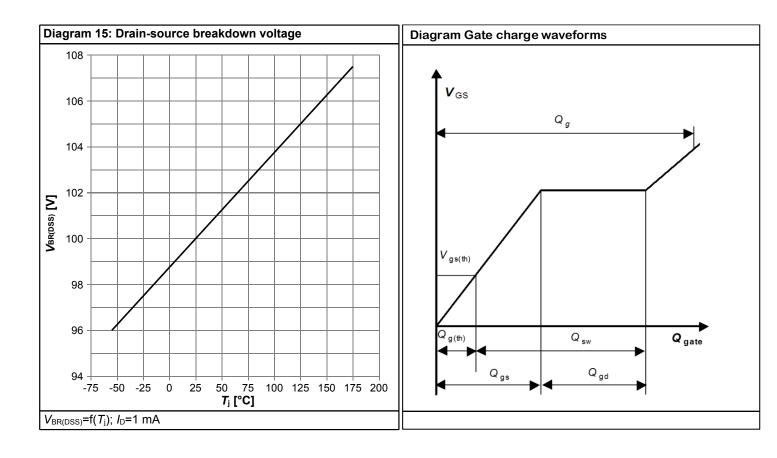






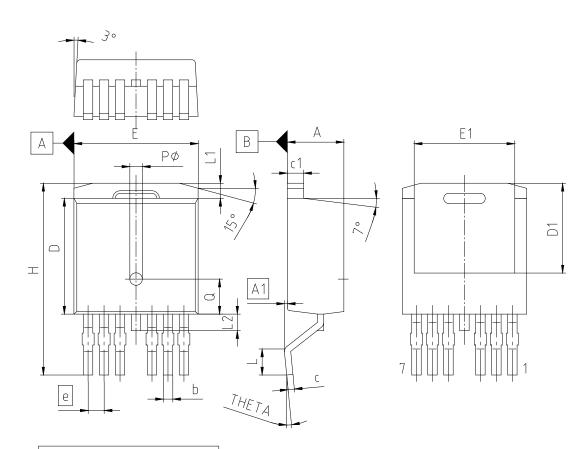








# 5 Package Outlines



PACKAGE - GROUP NUMBER:	PG-TO2	63-7-U02					
DIMENSIONS	MILLIMETERS						
DIMENSIONS	MIN.	MAX.					
Α	4.30	4.70					
A1	0.00	0.25					
b	0.65	0.85					
С	0.45	0.60					
c1	1.25	1.40					
D	9.00	9.40					
D1	6.86	7.42					
E	9.68	10.08					
E1	7.70	8.30					
е	1	.27					
N	7						
Н	14.61	15.88					
L	1.78	2.79					
L1	0.00	1.60					
L2	0.00	1.78					
THETA	0° - 8°						
PØ	0.90	1.10					
Q	2.78						

Figure 1 Outline PG-TO263-7, dimensions in mm

# StrongIRFET<sup>™</sup> 2 Power-Transistor IPF016N10NF2S



#### **Revision History**

IPF016N10NF2S

Revision: 2022-09-23, Rev. 2.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2022-09-23	Release of final version

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Final Data Sheet 11 Rev. 2.0, 2022-09-23